Application/Control No. Applicant(s)/Patent Under Reexamination 10/648,172 LEE, SUNG-KWON Notice of References Cited Examiner Art Unit Page 1 of 1 Kin-Chan Chen 1765 **U.S. PATENT DOCUMENTS** Date **Document Number** Name Classification Country Code-Number-Kind Code MM-YYYY US-2005/0037605 02-2005 Kim et al. 438/622 438/692 US-6,632,744 10-2003 Imai et al. В US-6,548,423 04-2003 Plat et al. 438/780 С D US-6,200,907 03-2001 Wang et al. 438/718 US-6,020,269 02-2000 Wang et al. 438/717 Ε US-6,171,763 01-2001 Wang et al. 430/318 F 11-2004 438/623 US-6,815,333 Townsend et al. G US-6,627,557 09-2003 Seta et al. 438/717 Н US-6,503,830 01-2003 Miyata, Koji-438/637 1 US-J US-US-US-М FOREIGN PATENT DOCUMENTS **Document Number** Date Name Classification Country Country Code-Number-Kind Code MM-YYYY Ν 0 Ρ Q R s T **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U ٧

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